

OSM/EE DECISION SHEET

Category	Standard:		Clause	Document no.
ITAV	EN 62368-1:2014 + A11:2017 EN IEC 62368-1:2020 + A11:2020 EN IEC 62368-1:2024 + A11:2024		Annex T.6	OSM-EE 18/3 rev 1
Subject		Key words		Meeting
Loose enclosure parts inside equipment after impact test		Enclosure, impact test		London 2018 Helsinki 2024

Question

If a part of the enclosure is loosen/detached as a result of the impact test (T.6) and ends up within the equipment. How should it be handled with regard to creepage and clearance?

Should it only be considered to affect creepage and clearance where it lands or should it be moved around (using 10N test of T.2 or similar method)?

Is it any different for conductive parts (that might bridge insulation) and none conductive parts (that might create shorter creepage distances than the original construction)?

Decision

If conductive loose parts occur after the impact test, it must be checked that it cannot result in any hazardous situation (by placing the loose part in the worst case possible position within the equipment)

Confirmed by TC108 at Busan, Korea, Oct 2018

Explanatory notes

In Helsinki 2024, OSM-EE decision 18/3 was modified with following changes:

- add 3rd and 4th editions of EN IEC 62368-1
- change category from OFF to ITAV